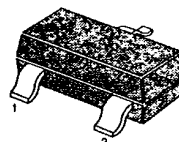


MMBT4123**NPN EPITAXIAL SILICON TRANSISTOR****GENERAL PURPOSE TRANSISTOR****ABSOLUTE MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$)**

Characteristic	Symbol	Rating	Unit
Collector-Base Voltage	V_{CB0}	40	V
Collector-Emitter Voltage	V_{CE0}	30	V
Emitter-Base Voltage	V_{EB0}	5	V
Collector Current	I_C	200	mA
Collector Dissipation	P_C	350	mW
Storage Temperature	T_{stg}	150	$^\circ\text{C}$
Thermal Resistance Junction to Ambient	$R_{th(j-a)}$	357	$^\circ\text{C/W}$

SOT-23



1. Base 2. Emitter 3. Collector

ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)

Characteristic	Symbol	Test Condition	Min	Max	Unit
Collector-Base Breakdown Voltage	BV_{CB0}	$I_C = 10\mu\text{A}$, $I_E = 0$	40		V
* Collector-Emitter Breakdown Voltage	BV_{CE0}	$I_C = 1\text{mA}$, $I_E = 0$	30		V
Emitter-Base Breakdown Voltage	BV_{EB0}	$I_E = 10\mu\text{A}$, $I_C = 0$	5		V
Collector Cutoff Current	I_{CB0}	$V_{CB} = 20\text{V}$, $I_E = 0$		50	nA
Emitter Cutoff Current	I_{EB0}	$V_{BE} = 3\text{V}$, $I_C = 0$		50	nA
* DC Current Gain	h_{FE}	$V_{CE} = 1\text{V}$, $I_C = 2\text{mA}$	50	150	
		$V_{CE} = 1\text{V}$, $I_C = 50\text{mA}$	25		
* Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 50\text{mA}$, $I_B = 5\text{mA}$		0.3	V
* Base-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = 50\text{mA}$, $I_B = 5\text{mA}$		0.95	V
Current Gain-Bandwidth Product	f_T	$V_{CE} = 20\text{V}$, $I_C = 10\text{mA}$, $f = 100\text{MHz}$	250		MHz
Collector Output Capacitance	C_{ob}	$V_{CB} = 5\text{V}$, $I_E = 0$, $f = 100\text{MHz}$		4	pF
Collector Input Capacitance	C_{ib}	$V_{BE} = 0.5\text{V}$, $I_C = 0$, $f = 100\text{KHz}$		8	pF
Collector-Base Capacitance	C_{cb}	$V_{CB} = 5\text{V}$, $I_E = 0$, $f = 100\text{KHz}$		4	pF
Noise Figure	NF	$V_{CE} = 5\text{V}$, $I_C = 100\mu\text{A}$, $R_s = 1\text{k}\Omega$ Noise Bandwidth = 10Hz to 15.7KHz		6	dB

* Pulse Test: $PW \leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Marking

